INTEGRATED CIRCUITS



Product specification Supersedes data of 1995 Nov 14 IC23 Data Handbook 1998 Feb 19



Philips Semiconductors

74LVT574

FEATURES

- Inputs and outputs on opposite side of package allow easy interface to microprocessors
- 3-State outputs for bus interfacing
- Common output enable
- TTL input and output switching levels
- Input and output interface capability to systems at 5V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted
- No bus current loading when output is tied to 5V bus
- Power-up 3-State
- Power-up reset
- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model

QUICK REFERENCE DATA

DESCRIPTION

The LVT574 is a high-performance BiCMOS product designed for V_{CC} operation at 3.3V.

This device is an 8-bit, edge triggered register coupled to eight 3-State output buffers. The two sections of the device are controlled independently by the clock (CP) and Output Enable (\overline{OE}) control gates. The state of each D input (one set-up time before the Low-to-High clock transition) is transferred to the corresponding flip-flop's Q output.

The 3-State output buffers are designed to drive heavily loaded 3-State buses, MOS memories, or MOS microprocessors. The active-Low Output Enable ($\overline{\text{OE}}$) controls all eight 3-State buffers independent of the clock operation.

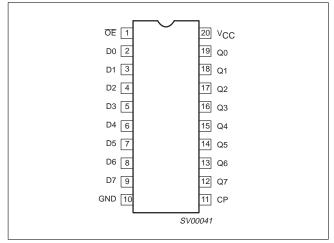
When \overline{OE} is Low, the stored data appears at the outputs. When \overline{OE} is High, the outputs are in the High-impedance "off" state, which means they will neither drive nor load the bus.

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay CP to Qn	$C_L = 50 pF;$ $V_{CC} = 3.3 V$	3.6 4.3	ns
C _{IN}	Input capacitance	V _I = 0V or 3.0V	4	pF
C _{OUT}	Output capacitance	Outputs disabled; V _{I/O} = 0V or 3.0V	8	pF
I _{CCZ}	Total supply current	Outputs disabled; V _{CC} = 3.6V	0.13	mA

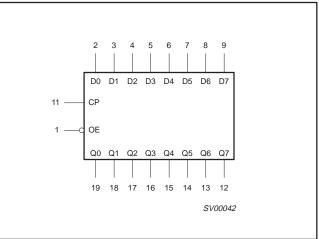
ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
20-Pin Plastic SOL	-40°C to +85°C	74LVT574 D	74LVT574 D	SOT163-1
20-Pin Plastic SSOP Type II	–40°C to +85°C	74LVT574 DB	74LVT574 DB	SOT339-1
20-Pin Plastic TSSOP Type I	-40°C to +85°C	74LVT574 PW	74LVT574PW DH	SOT360-1

PIN CONFIGURATION

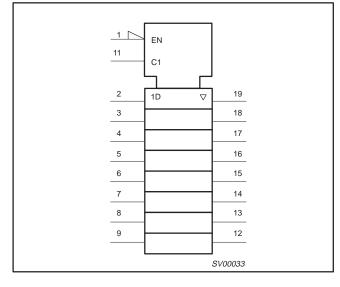


LOGIC SYMBOL



74LVT574

LOGIC SYMBOL (IEEE/IEC)



PIN DESCRIPTION

PIN NUMBER	SYMBOL	FUNCTION
1	ŌE	Output enable input (active-low)
2, 3, 4, 5, 6, 7, 8, 9	D0-D7	Data inputs
19, 18, 17, 16, 15, 14, 13, 12	Q0-Q7	Data outputs
11	СР	Clock pulse input (active rising edge)
10	GND	Ground (0V)
20	V _{CC}	Positive supply voltage

FUNCTION TABLE

	INPUTS		INTERNAL	OUTPUTS	OPERATING
OE	СР	Dn	REGISTER	Q0 – Q7	MODE
L	$\stackrel{\uparrow}{\uparrow}$	l h	L H	L H	Load and read register
L	\$	Х	NC	NC	Hold
Н	Х	Х	NC	Z	Disable outputs

H = High voltage level

High voltage level one set-up time prior to the Low-to-High clock transition h =

L = Low voltage level

Low voltage level one set-up time prior to the Low-to-High clock transition 1 =

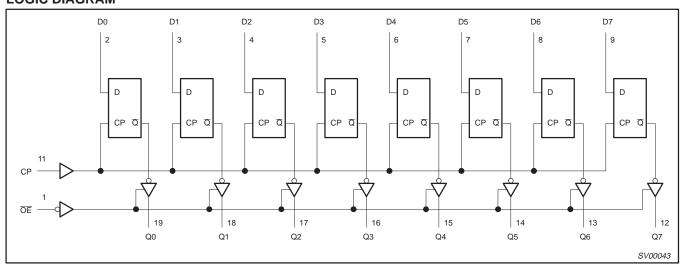
NC= No change

Don't care Х =

High impedance "off" state =

Z ↑ Low-to-High clock transition = Ţ not a Low-to-High clock transition =

LOGIC DIAGRAM



74LVT574

ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT	
V _{CC}	DC supply voltage		-0.5 to +4.6	V	
I _{IK}	DC input diode current	V ₁ < 0	-50	mA	
VI	DC input voltage ³		-0.5 to +7.0	V	
I _{OK}	DC output diode current	V _O < 0	-50	mA	
V _{OUT}	DC output voltage ³	Output in Off or High state	-0.5 to +7.0	V	
		Output in Low state	128		
lout	DC output current	Output in High state	-64	mA	
T _{stg}	Storage temperature range		-65 to 150	°C	

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT		
STMIDOL	PARAMETER	MIN	MAX		
V _{CC}	DC supply voltage	2.7	3.6	V	
VI	Input voltage	0	5.5	V	
V _{IH}	High-level input voltage	2.0		V	
V _{IL}	Input voltage		0.8	V	
I _{OH}	High-level output current		-32	mA	
la	Low-level output current		32	mA	
IOL	Low-level output current; current duty cycle \leq 50%, f \geq 1kHz		64	IIIA	
$\Delta t/\Delta v$	Input transition rise or fall rate; outputs enabled		10	ns/V	
T _{amb}	Operating free-air temperature range	-40	+85	°C	

DC ELECTRICAL CHARACTERISTICS

					LIMITS			
SYMBOL	PARAMETER	TEST CONDITIONS		Temp =	-40°C to +85°C		UNIT	
				MIN	TYP ¹	MAX		
V _{IK}	Input clamp voltage	$V_{CC} = 2.7V; I_{IK} = -18mA$			-0.9	-1.2	V	
		$V_{CC} = 2.7$ to 3.6V; $I_{OH} = -100\mu A$		V _{CC} -0.2	V _{CC} -0.1			
V _{OH}	High-level output voltage	V _{CC} = 2.7V; I _{OH} = -8mA		2.4	2.5		V	
		V _{CC} = 3.0V; I _{OH} = -32mA	2.0	2.2				
		V _{CC} = 2.7V; I _{OL} = 100μA		1	0.1	0.2		
		V _{CC} = 2.7V; I _{OL} = 24mA			0.3	0.5		
V _{OL}	Low-level output voltage	V _{CC} = 3.0V; I _{OL} = 16mA		0.25	0.4	V		
		V _{CC} = 3.0V; I _{OL} = 32mA		0.3	0.5			
		V _{CC} = 3.0V; I _{OL} = 64mA		0.4	0.55			
V _{RST}	Power-up output low voltage ⁵	V_{CC} = 3.6V; I_{O} = 1mA; V_{I} = GND or V_{CC}	1	0.13	0.55	V		
		V _{CC} = 0 or 3.6V; V _I = 5.5V		1	1	10		
	Input leakage current	$V_{CC} = 3.6V; V_I = V_{CC} \text{ or } GND$	Control pins		±0.1	±1	μA	
łı	input leakage current	$V_{CC} = 3.6V; V_1 = V_{CC}$	Dete size4		0.1	1	μΑ	
		$V_{CC} = 3.6V; V_1 = 0$	Data pins ⁴		-1	-5		
I _{OFF}	Output off current	$V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$	•		1	±100	μA	
		$V_{CC} = 3V; V_{I} = 0.8V$	75	150				
I _{HOLD}	Bus Hold current A inputs ⁷	$V_{CC} = 3V; V_{I} = 2.0V$	-75	-150		μA		
		$V_{CC} = 0V$ to 3.6V; $V_{CC} = 3.6V$	±500					
I_{EX}	Current into an output in the High state when $V_O > V_{CC}$	V _O = 5.5V; V _{CC} = 3.0V			60	125	μΑ	
I _{PU/PD}	Power up/down 3-State output current ³	$V_{CC} \le 1.2V$; $V_O = 0.5V$ to V_{CC} ; $V_I = GND$ OE/OE = Don't care	or V_{CC} ;		1	±100	μΑ	
I _{OZH}	3-State output High current	V_{CC} = 3.6V; V_{O} = 3V; V_{I} = V_{IL} or V_{IH}			1	5	μΑ	
I _{OZL}	3-State output Low current	V_{CC} = 3.6V; V_{O} = 0.5V; V_{I} = V_{IL} or V_{IH}			1	-5	μΑ	
I _{CCH}		V_{CC} = 3.6V; Outputs High, V_{I} = GND or V_{CC}		0.13	0.19			
I _{CCL}	Quiescent supply current ³	V_{CC} = 3.6V; Outputs Low, V_{I} = GND or V		3	12	mA		
I _{CCZ}	1	V _{CC} = 3.6V; Outputs Disabled; V _I = GND	or V _{CC} , $I_{O} = 0^5$		0.13	0.19		
ΔI_{CC}	Additional supply current per input pin ²	$V_{CC} = 3V$ to 3.6V; One input at V_{CC} -0.6 Other inputs at V_{CC} or GND	Ι,		0.1	0.2	mA	

NOTES:

1. All typical values are at $V_{CC} = 3.3V$ and $T_{amb} = 25^{\circ}C$. 2. This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND

3. This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From V_{CC} = 1.2V to V_{CC} = $3.3V \pm 0.3V$ a transition time of 100µsec is permitted. This parameter is valid for T_{amb} = 25°C only. 4. Unused pins at V_{CC} or GND.

5. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

6. I_{CCZ} is measured with outputs pulled to V_{CC} or GND.

7. This is the bus hold overdrive current required to force the input to the opposite logic state.

AC CHARACTERISTICS

GND = 0V, $t_R = t_F = 2.5$ ns, $C_L = 50$ pF, $R_L = 500\Omega$; $T_{amb} = -40^{\circ}$ C to +85°C.

SYMBOL	PARAMETER	WAVEFORM	٧ _c	$_{ m C}$ = 3.3V \pm 0	.3V	V _{CC} :	UNIT	
			MIN	TYP ¹	MAX	MIN	MAX	
f _{MAX}	Maximum clock frequency	NO TAG	150			150		ns
t _{PLH} t _{PHL}	Propagation delay CP to Qn	NO TAG	1.7 2.4	3.6 4.3	5.4 5.9		6.2 6.6	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	NO TAG NO TAG	1.0 1.3	2.9 3.4	4.8 5.1		5.9 6.2	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	NO TAG NO TAG	1.9 1.7	4.0 3.2	5.5 4.5		5.9 4.5	ns

NOTE:

1. All typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.

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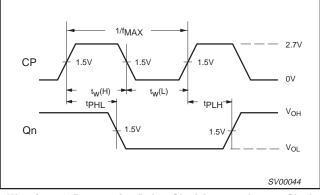
AC SETUP REQUIREMENTS

GND = 0V, $t_R = t_F = 2.5$ ns, $C_L = 50$ pF, $R_L = 500\Omega$; $T_{amb} = -40$ °C to +85°C.

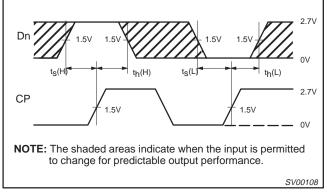
SYMBOL	PARAMETER	WAVEFORM	V _{CC} = 3.	$3V \pm 0.3V$	V _{CC} = 2.7V	UNIT
			MIN	MAX	MIN	
t _S (H) t _S (L)	Setup time, High or Low, Dn to CP	NO TAG	2.0 2.0		2.4 2.4	ns
T _H (H) T _H (L)	Hold time, High or Low, Dn to CP	NO TAG	0.3 0.3		0 0	ns
T _W (H)	CP pulse width High or Low	NO TAG	3.3 3.3		3.3 3.3	ns

AC WAVEFORMS

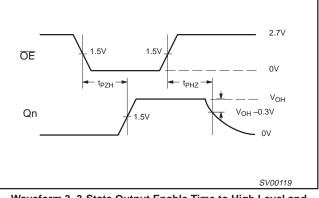
 V_{M} = 1.5V, V_{IN} = GND to 2.7V



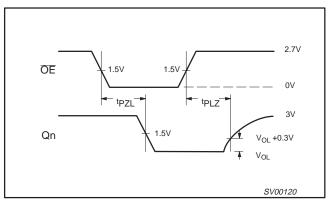
Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency



Waveform 2. Data Setup and Hold Times



Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level

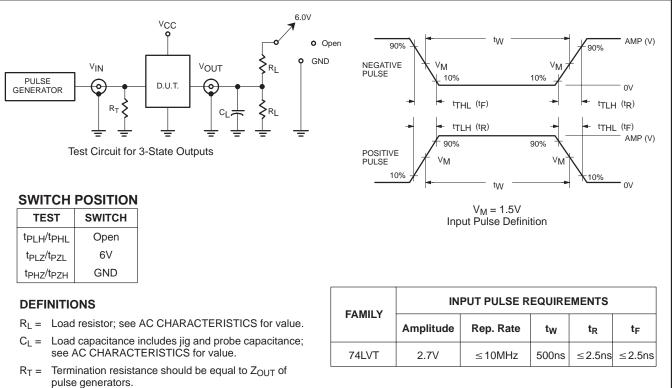


Waveform 4. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

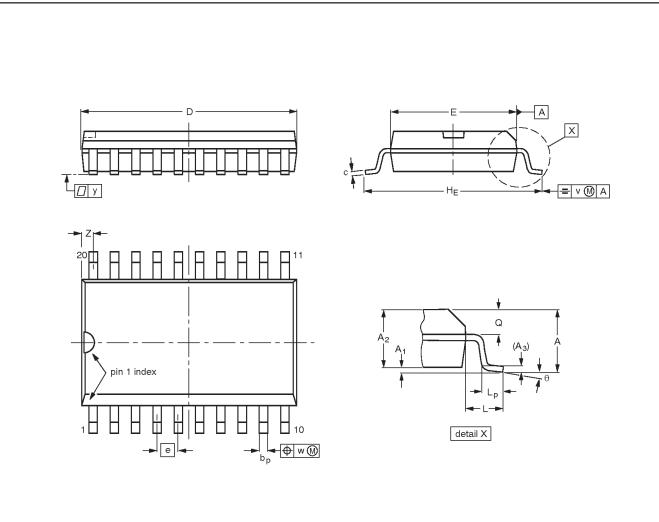
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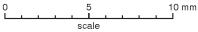
3.3V Octal D-type flip-flop (3-State)

TEST CIRCUIT AND WAVEFORM



SO20: plastic small outline package; 20 leads; body width 7.5 mm





DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	Α ₁	A ₂	A ₃	bp	с	D ⁽¹⁾	E ⁽¹⁾	е	Η _E	L	Lp	Q	v	w	У	z ⁽¹⁾	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	13.0 12.6	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8 ⁰
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.51 0.49	0.30 0.29	0.050	0.42 0.39	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	0 ⁰

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

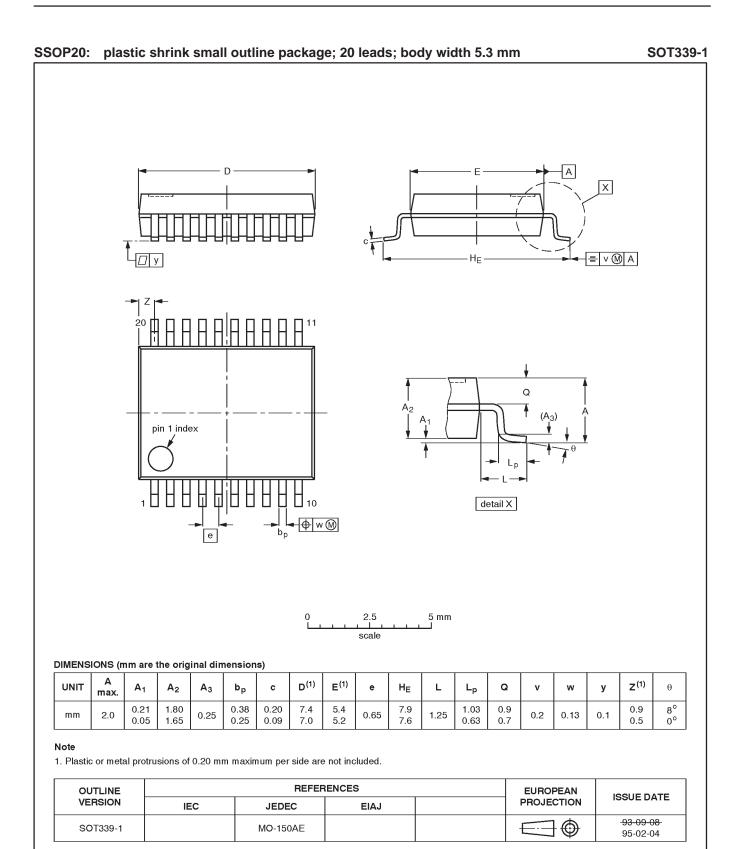
OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT163-1	075E04	MS-013AC				-92-11-17 95-01-24

Product specification

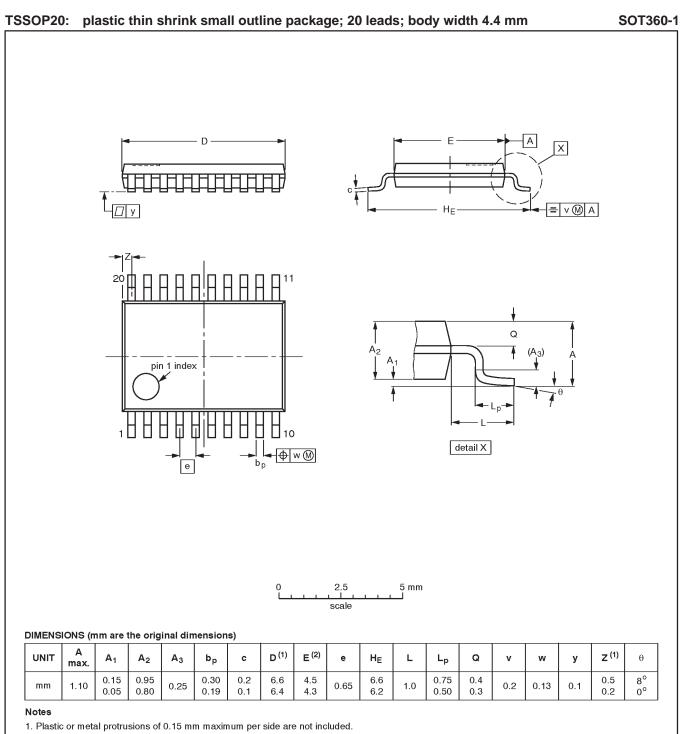
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SOT163-1

74LVT574



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2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	1550E DATE
SOT360-1		MO-153AC			-93-06-16 95-02-04

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NOTES

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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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print code

Document order number:

Date of release: 05-96 9397-750-03542

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